Overview

iEDX-150T Series

The iEDX-150T Series is a plating thickness measurement device ideal for product development, quality control, and process management. Recent innovations have improved precision, repeatability, and cost-effectiveness, ensuring accurate and easy measurements. Its advanced specifications distinguish it from earlier XRF models.

◎ Specification

Model	iEDX-150T Series			
	sp30	mp30	wT 30	uT7.5, 15, 30
Ⅰ Major Features				
1 X-Ray	W Target, 50Kev 1mA, General Type Tube (X-Ray Size 400um)	W Target, 50Kev 1mA, Micro Focus Type Tube (X-Ray Size 100um)	W Target, 50Kev 1mA, Micro Focus Type Tube (X-Ray Size 100um)	W Target, 50Kev 1mA, Micro Focus Type Tube (X-Ray Size 100um)
2 Detector	SDD (Silicon Drift Dector)	SDD (Silicon Drift Dector)	SDD (Silicon Drift Dector)	FSDD (Fast SDD)
3 Resolution	125eV FWHM at Mn Kα	125eV FWHM at Mn Kα	125eV FWHM at Mn Kα	123eV FWHM at Mn Kα
4 Collimator	0.3mm, 0.5mm, 1mm	0.1mm ~ 1mm	0.1mm ~ 1mm	7.5um, 15um, 30um
5 CCD Camera	40 (X1, X2)	40 (X1, X2)	40 (X1, X2)	40 (X1, X2)
Ⅱ Performance				
1 Detection Limit	30nm	20nm	20nm~30nm	5nm
2 Accuracy	±5%	±3%	±3%	±1%
3 Repeatability	Cov 5%↓	Cov 3%↓	Cov 3%↓	Cov 1%↓
Ⅲ Operation System				
1 Computer	Samsung, HP, Lenovo			
2 HDD	250G			
3 OS	Windows10			
4 Software	Multi-Ray 2.x.x			
	▶ Program Registration Number : 2009-01-199-004565			
Ⅳ Safety				
1 Radiation Protection	0.2us/h			
2 Design Approval No.	NSSC1.30RG001.03			
Ⅴ Application				
1 Measurable Element	Inorganic Substances with Atomic Numbers 22 to 92			
2 Measurable Range (um)	Atomic No. 22-24 : 0~25, Atomic No. 25-40 : 0~35, Atomic No. 41-51 : 0~50, Atomic No. 52-82 : 0~10			
Ⅵ Additional				
1 Print Format	PDF, Excel			
2 Option	Standard Specimen		※ CoV=(Standard Deviation/Average)X100	

Model:

iEDX-150T sp30

The iEDX-150T sp30 model is an entry-level product in ISP's XRF lineup, designed for easy measurement of general and special plating. Its automated stage simplifies operation, while the streamlined analysis method allows for quick thickness assessments. This model features specifications that distinguish it from earlier XRFs.

iEDX 150T sp30
Isp Energy Dispersive X-ray

◎ Specification

Model	iEDX-150T sp30
I Major Features	
1 X-Ray	W Target, 50Kev 1mA, General Type Tube (X-Ray Size 400um)
2 Stage System (Stroke)	160X160X100 mm(WXDXH) ▶ 3-axis Motorized
3 Detector	SDD (Silicon Drift Dector)
4 Resolution	125eV FWHM at Mn Kα
5 Collimator	0.3mm, 0.5mm, 1mm (auto change)
6 CCD Camera	40 (X1, X2)
II Performance	
1 Detection Limite	30nm
2 Accuracy	±5%
3 Repeatability	Cov 5%↓
III Operation System	
1 Computer	Samsung, HP, Lenovo
2 HDD	250G
3 OS	Windows10
4 Software	Multi-Ray 2.x.x ▶ Program Registration Number : 2009-01-199-004565
IV Safety	
1 Radiation Protection	0.2us/h
2 Design Approval No.	NSSC1.30RG001.03
V Application	
1 Measurable Element	ZnNi/Fe, Zn/Fe, Ni/Fe, Ni/Cu, Sn/Cu, Au/Ni/Cu
2 Measurable Range (um)	Atomic No. 22-24 : 0~25, Atomic No. 25-40 : 0~35, Atomic No. 41-51 : 0~50, Atomic No. 52-82 : 0~10
VI Additional	
1 Print Format	PDF, Excel
2 Option	Standard Specimen

Model:

iEDX-150T mp30

The iEDX-150T mp30 model is a high-end product in ISP's XRF lineup, offering advanced plating thickness measurement. It accurately measures general plating, special plating, and ENEPIG. Its user-friendly operation, automated stage, and efficient analysis method enable quick assessments, distinguishing it from earlier XRF models.

iEDX 150T mp30
Isp Energy Dispersive X-ray

◎ Specification

Model	iEDX-150T mp30
Ⅰ Major Features	
1 X-Ray	W Target, 50Kev 1mA, Micro Focus Type Tube (X-Ray Size 100um)
2 Stage System (Stroke)	160X160X100 mm(WXDXH) ▶ 3-axis Motorized
3 Detector	SDD (Silicon Drift Dector)
4 Resolution	125eV FWHM at Mn Kα
5 Collimator	0.1mm ~ 1mm
6 CCD Camera	40 (X1, X2)
Ⅱ Performance	
1 Detection Limite	20nm
2 Accuracy	±3%
3 Repeatability	Cov 3%↓
Ⅲ Operation System	
1 Computer	Samsung, HP, Lenovo
2 HDD	250G
3 OS	Windows10
4 Software	Multi-Ray 2.x.x ▶ Program Registration Number : 2009-01-199-004565
IV Safety	
1 Radiation Protection	0.2us/h
2 Design Approval No.	NSSC1.30RG001.03
V Application	
1 Measurable Element	ZnNi/Fe, Zn/Fe, Ni/Fe, Ni/Cu, Sn/Cu, Au/Ni/Cu
2 Measurable Range (um)	Atomic No. 22-24 : 0~25, Atomic No. 25-40 : 0~35, Atomic No. 41-51 : 0~50, Atomic No. 52-82 : 0~10
VI Additional	
1 Print Format	PDF, Excel
2 Option	Standard Specimen, RoHS Function can be added

Model:

iEDX -150WT

The iEDX-150WT model is an equipment for measuring PCBs and glass in ISP's XRF lineup. It features both entry-level and high-end options, primarily for measuring gold (Au) and nickel (Ni) on copper (Cu). Its automated stage simplifies operation, while the streamlined analysis method allows for quick thickness assessments. This model features specifications that distinguish it from earlier XRFs.

◎ Specification

Model	iEDX-150WT
Ⅰ Major Features	
1 X-Ray	W Target, 50Kev 1mA, Micro Focus Type Tube (X-Ray Size 100um)
2 Stage System (Stroke)	310 X 310 X 10 mm (WXDXH), 520 X 520 X 10 mm (WXDXH) ▶ 3-axis Motorized
3 Detector	SDD (Silicon Drift Dector)
4 Resolution	125eV FWHM at Mn Kα
5 Collimator	0.1mm ~ 1mm
6 CCD Camera	40 (X1, X2)
Ⅱ Performance	
1 Detection Limite	20nm
2 Accuracy	±3%
3 Repeatability	Cov 3%↓
Ⅲ Operation System	
1 Computer	Samsung, HP, Lenovo
2 HDD	250G
3 OS	Windows10
4 software	Multi-Ray 2.x.x ▶ Program Registration Number : 2009-01-199-004565
Ⅳ Safety	
1 Radiation Protection	0.2us/h
2 Design Approval No.	NSSC1.30RG001.03
Ⅴ Application	
1 Measurable Element	Sn/Cu, Au/Ni/Cu, Sn/Ni/Cu, Ag/Cu
2 Measurable Range (um)	Atomic No. 22-24 : 0~25, Atomic No. 25-40 : 0~35, Atomic No. 41-51 : 0~50, Atomic No. 52-82 : 0~10
Ⅵ Additional	
1 Print Format	PDF, Excel
2 Option	Standard Specimen

Model:

iEDX -150uT 7.5, 15, 30

The iEDX-150uT model is ISP's top-tier thickness measurement equipment, capable of measuring micro patterns at 7.5 μm, 15 μm, and 30 μm using PolyCapillary technology. With the rise of miniaturized products, our device effectively meets the increasing demand for ultra-fine pattern measurements. This model features specifications that distinguish it from earlier XRFs.

iEDX-150μT

◎ Specification

Model	IEDX-150uT 7.5, 15, 30
I Major Features	
1 X-Ray	W Target, 50Kev 1mA, Micro Focus Type Tube (X-Ray Size 100um)
2 Stage System (Stroke)	160X160X100 mm(WXDXH) ▶ 3-axis Motorized
3 Detector	FSDD (Fast Silicon Drift Detector)
4 Resolution	123eV FWHM at Mn Kα
5 Collimator	7.5um, 15um, 30um
6 CCD Camera	40 (X1, X2)
II Performance	
1 Detection Limite	5nm
2 Accuracy	±1%
3 Repeatability	Cov 1% ↓
III Operation System	
1 Computer	Samsung, HP, Lenovo
2 HDD	250G
3 OS	Windows10
4 Software	Multi-Ray 2.x.x ▶ Program Registration Number : 2009-01-199-004565
IV Safety	
1 Measurable Element	0.2us/h
2 Design Approval No.	NSSC1.30RG001.03
V Application	
1 Measurable Element	Zn, Ni, ZnNi, Au, Ag, Pd, Cu, Sn, ENIG, ENEPIG
2 Measurable Range (um)	Atomic No. 22-24 : 0~25, Atomic No. 25-40 : 0~35, Atomic No. 41-51 : 0~50, Atomic No. 52-82 : 0~10
VI Additional	
1 Print Format	PDF, Excel
2 Option	Standard Specimen